



WANSEMI
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WX047N02PA

Enhancement Mode N-Channel Power MOSFET

PDFN5X6/NMOS/20V/±12V/0.8V/55A/4.7mΩ

Rev0.1

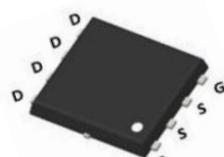
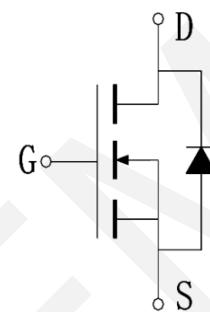


20V, 4.7mΩ, 55A, Single N-Channel

1. Features

- ◆ 20V MOSFET technology
- ◆ Low on-state resistance
- ◆ Fast switching
- ◆ $V_{GS} \pm 12V$
- ◆ 100% RG Tested
- ◆ 100% UIS Tested

V_{DS}	$R_{DS(on)}$ Typ.	I_D Max.
20V	4.7mΩ @ 4.5V	55A
	6.3mΩ @ 2.5V	



PDFN5X6
Pin Description

Schematic Diagram

3. Package Marking and Ordering Information

Part no.	Marking	Package	PCS/Reel	PCS/CTN.
WX047N02PA	047N02	PDFN5X6	5,000	50,000

4. Absolute Max Ratings at $T_a=25^\circ C$ (Note1)

Parameter	Symbol	Maximum	Units
Drain to Source Voltage	V_{DSS}	20	V
Gate to Source Voltage	V_{GSS}	± 12	V
Drain Current (DC)	I_D	55	A
Drain Current (Pulse), $PW \leq 300\mu s$	I_{DP}	220	A
Total Dissipation	P_D	37	W
Avalanche Energy, Single Pulsed	E_{AS}	64	mJ
Junction Temperature	T_j	150	°C
Storage Temperature	T_{stg}	-55 to +150	°C

Note 1: Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.



5.Thermal Resistance Ratings

Parameter	Symbol	Value	Unit
Junction to case	R_{AJC}	3.2	°C/W

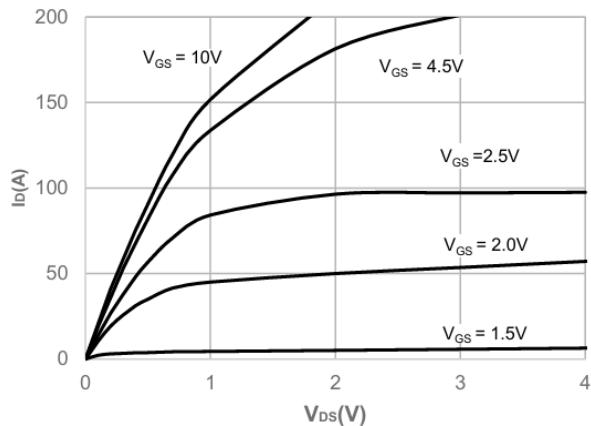
Note 2: When mounted on 1 inch square copper board $t \leq 10\text{sec}$ The value in any given application depends on the user's specific board design.

6.Electrical Characteristics at $T_a=25^\circ\text{C}$ (Note 3)

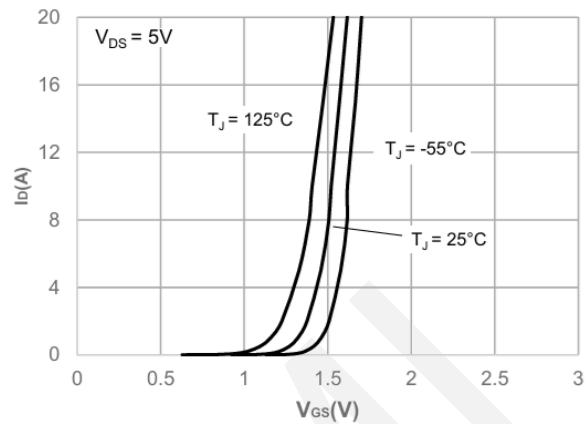
Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Units
Drain to Source Breakdown Voltage	$V_{(BR)DSS}$	$I_D = 250\mu\text{A}, V_{GS} = 0\text{V}$	20	-	-	V
Zero-Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 20\text{V}, V_{GS} = 0\text{V}$	-	-	1	μA
Gate to Source Leakage Current	I_{GSS}	$V_{GS} = \pm 12\text{V}, V_{SS} = 0\text{V}$	-	-	± 100	nA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_{DS}=250\mu\text{A}$	0.5	0.8	1.1	V
Static Drain to Source On-State Resistance	$R_{DS(on)}$	$I_D = 25\text{A}, V_{GS} = 4.5\text{V}$	-	4.7	5.6	$\text{m}\Omega$
		$I_D = 15\text{A}, V_{GS} = 2.5\text{V}$		6.3	8.5	$\text{m}\Omega$
Input Capacitance	C_{iss}	$V_{GS}=0\text{V}, V_{DS}=10\text{V},$ Frequency=1.0MHz	-	2007	-	pF
Output Capacitance	C_{oss}		-	278	-	pF
Reverse Transfer Capacitance	C_{rss}		-	252	-	pF
Turn-ON Delay Time	$t_{d(on)}$	$V_{DD} = 10\text{V}, I_D = 20\text{A},$ $V_{GS} = 4.5\text{V}, R_G = 3\Omega$	-	12	-	ns
Rise Time	t_r		-	33	-	ns
Turn-OFF Delay Time	$t_{d(off)}$		-	48	-	ns
Fall Time	t_f		-	95	-	ns
Total Gate Charge	Q_g	$V_{DS} = 10\text{V},$ $V_{GS} = 0 \text{ to } 4.5\text{V},$ $I_D = 20\text{A}$	-	23	-	nC
	Q_{gs}		-	4	-	nC
	Q_{gd}		-	7	-	nC
Diode Forward Voltage	V_{FSD}	$I_S = 25\text{A}, V_{GS} = 0$	0.5	-	1.2	V

Note 3: Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

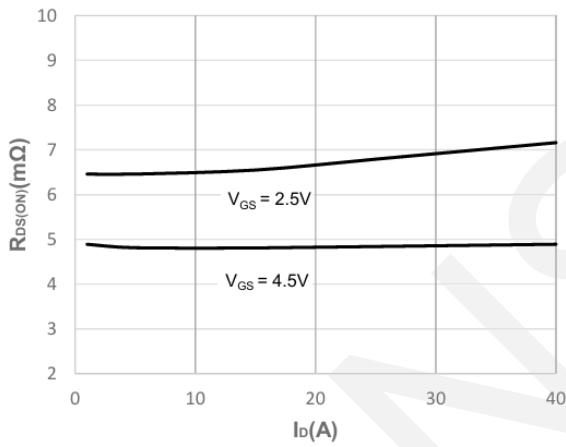
7.Typical electrical and thermal characteristics



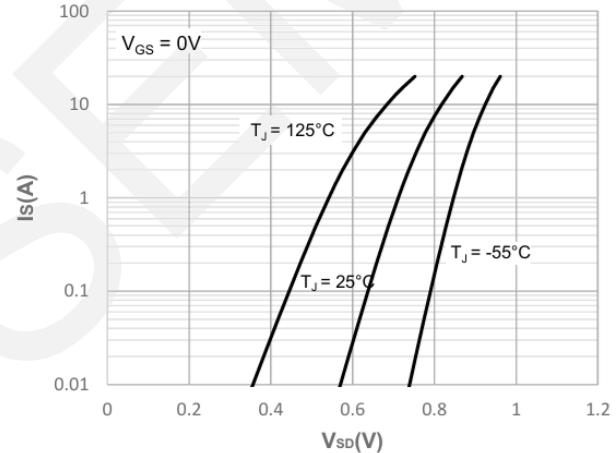
Output Characteristics



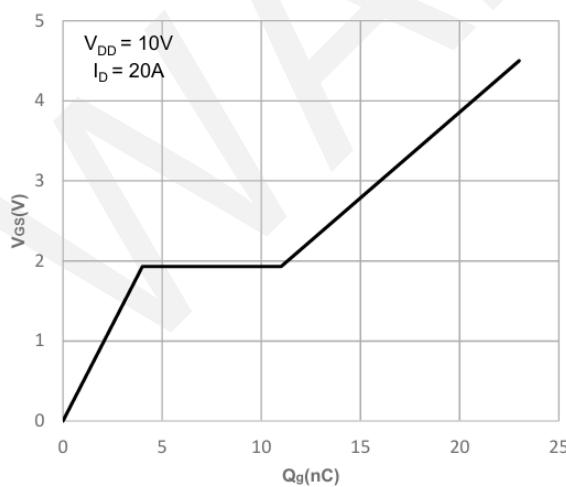
Transfer Characteristics



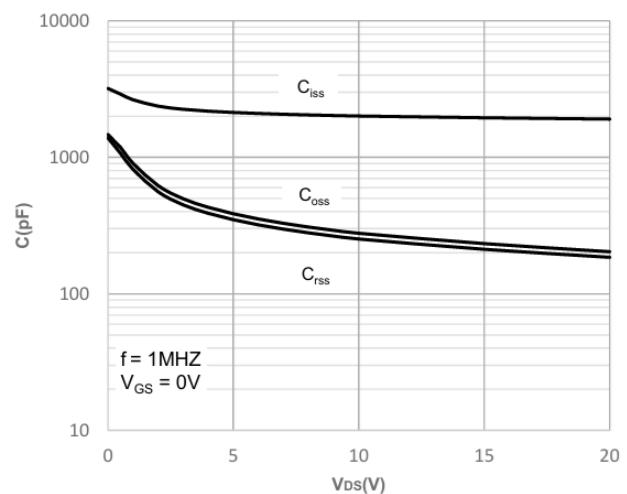
Rdson-Drain Current



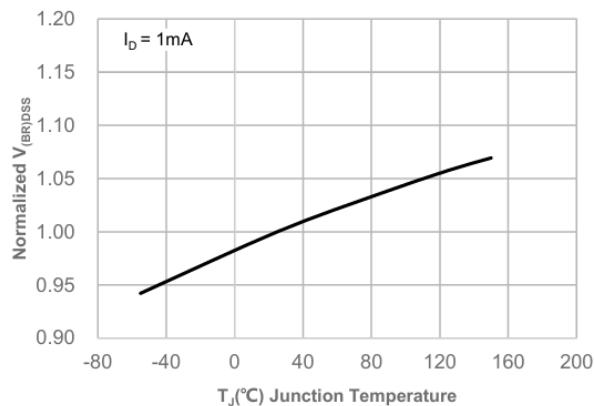
Body Diode Characteristic



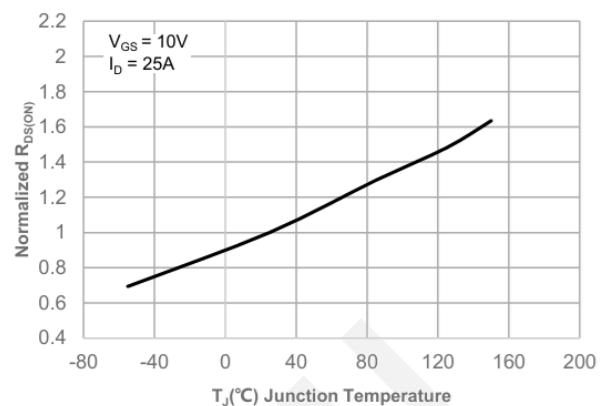
Gate Charge



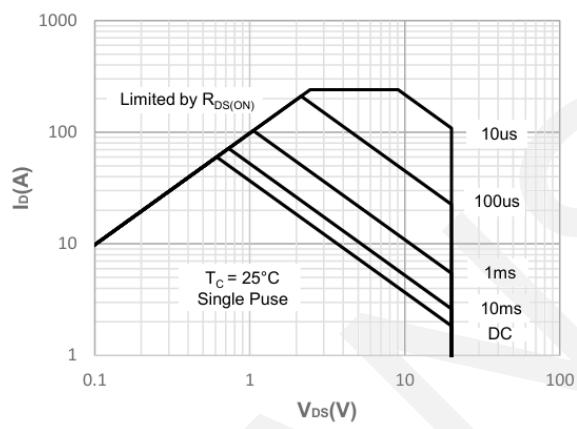
Capacitance Characteristics



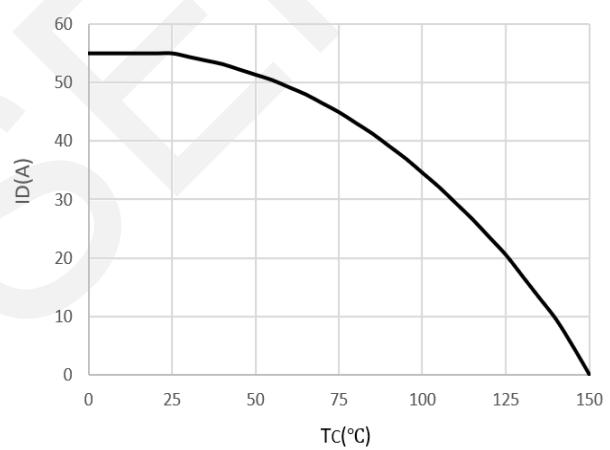
Normalized Breakdown Voltage vs.
Junction Temperature



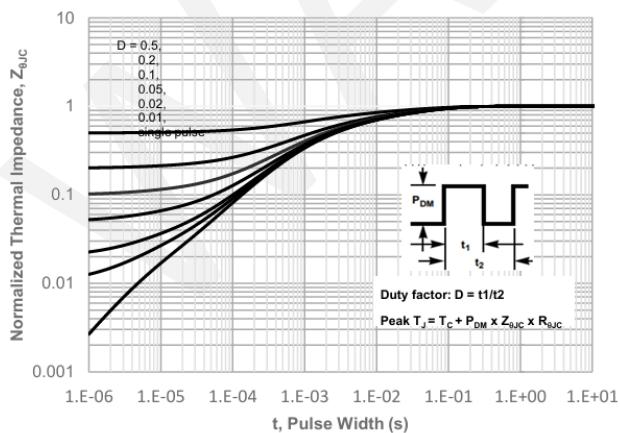
Normalized on Resistance vs.
Junction Temperature



Maximum Safe Operating Area



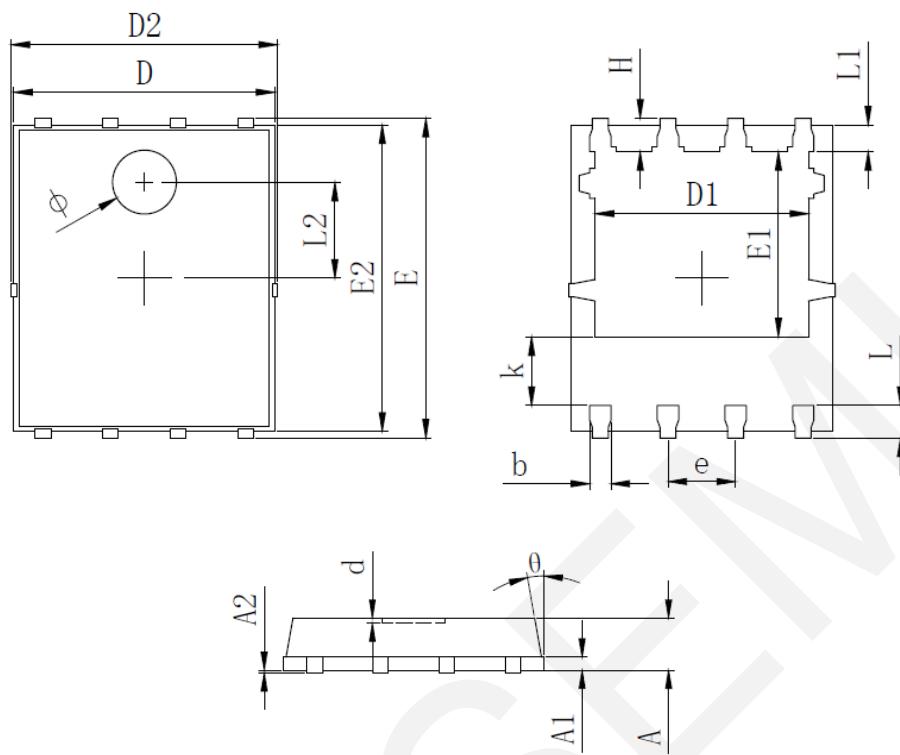
Maximum Continuous Drain Current
vs. Case Temperature



Maximum Effective Transient Thermal
Impedance, Junction-to-Case



8.Package Dimensions



SYMBOL	MILLIMETER		
	MIN	Typ.	MAX
A	0.900	1.000	1.100
A1	0.254 REF.		
A2	0~0.05		
D	4.824	4.900	4.976
D1	3.910	4.010	4.110
D2	4.924	5.000	5.076
E	5.924	6.000	6.076
E1	3.375	3.475	3.575
E2	5.674	5.750	5.826
b	0.350	0.400	0.450
e	1.270 TYP.		
L	0.534	0.610	0.686
L1	0.424	0.500	0.576
L2	1.800 REF.		
k	1.190	1.290	1.390
H	0.549	0.625	0.701
θ	8°	10°	12°
ϕ	1.100	1.200	1.300
d			0.100

9. Important Notice

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